



RYUKA.006AUS

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

|           |   |                         |   |                     |
|-----------|---|-------------------------|---|---------------------|
| Applicant | : | Masaki Takakuwa et al.  | ) | Group Art Unit 2881 |
|           |   |                         | ) |                     |
| Appl. No. | : | 10/624,423              | ) |                     |
|           |   |                         | ) |                     |
| Filed     | : | July 21, 2003           | ) |                     |
|           |   |                         | ) |                     |
| For       | : | ELECTRON BEAM EXPOSURE  | ) |                     |
|           |   | APPARATUS AND ELECTRON  | ) |                     |
|           |   | BEAM MEASUREMENT MODULE | ) |                     |
|           |   |                         | ) |                     |
| Examiner  | : | Paul M. Gurzo           | ) |                     |
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ELECTION & AMENDMENT

Hon. Commissioner  
of Patents and Trademarks  
Alexandria, VA 22313-1450

Dear Sir:

ELECTION:

This election is submitted in response to the office action mailed August 23, 2005 for the above-identified patent application.

The applicant elects, without prejudice, the invention group 2 directed to Figure 4 for further prosecution of this case. Claims 8-13 are readable on the invention group 2.